


<b>Search Notes</b> 	<b>Application/Control No.</b> 10575706	<b>Applicant(s)/Patent Under Reexamination</b> VAANANEN ET AL.
	<b>Examiner</b> THUAN NGUYEN	<b>Art Unit</b> 4145

SEARCHED			
Class	Subclass	Date	Examiner
370	235,232,230.1,230,229	10/22/2008	T.N.
709	235,232,230	10/22/2008	T.N.

SEARCH NOTES		
Search Notes	Date	Examiner
EAST text search (US-PGPUB,USPAT,FPRS,EPO,JPO,DERWENT,IBM_TDB)	10/22/2008	T.N.
EAST and PALM inventor search	10/22/2008	T.N.
IEEEXplore	10/22/2008	T.N.

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner

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